FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

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	AS	IMPEDANCE CONTROL OF REACTIVE SPUTTERING PROCESS by M. Kon et al. (Japan Soc. of Appl. Phys. 01-20								2003)			
	AT	COMPARISON C	I. (Surface 8	Coating Tech	nology (19	98)							
	AU THE EFFECT OF DEPOSITION TEMPERATURE by J.F. Chang et al. (Thin Solid Films 386 - 2001)							_*					
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